

# NTMFS4108N

## Power MOSFET

### 30 V, 35 A, Single N-Channel, SO-8 Flat Lead Package

#### Features

- Thermally and Electrically Enhanced Packaging Compatible with Standard SO-8 Package Footprint
- New Package Provides Capability of Inspection and Probe After Board Mounting
- Ultra Low  $R_{DS(on)}$  (at 4.5 V<sub>GS</sub>), Low Gate Resistance and Low Q<sub>G</sub>
- Optimized for Low Side Synchronous Applications
- High Speed Switching Capability

#### Applications

- Notebook Computer Vcore Applications
- Network Applications
- DC-DC Converters

#### MAXIMUM RATINGS (T<sub>J</sub> = 25°C unless otherwise noted)

Rating		Symbol	Value	Unit	
Drain-to-Source Voltage		V <sub>DSS</sub>	30	V	
Gate-to-Source Voltage		V <sub>GS</sub>	±20	V	
Continuous Drain Current (Note 1)	Steady State	T <sub>A</sub> = 25°C	I <sub>D</sub>	22	A
		T <sub>A</sub> = 85°C		16	
	t ≤ 10 s	T <sub>A</sub> = 25°C		35	
Power Dissipation (Note 1)	Steady State	T <sub>A</sub> = 25°C	P <sub>D</sub>	2.4	W
		t ≤ 10 s		6.25	
Continuous Drain Current (Note 2)	Steady State	T <sub>A</sub> = 25°C	I <sub>D</sub>	13.5	A
		T <sub>A</sub> = 85°C		10	
Power Dissipation (Note 2)	Steady State	T <sub>A</sub> = 25°C	P <sub>D</sub>	0.91	W
Pulsed Drain Current	tp = 10 μs	I <sub>DM</sub>	106	A	
Operating Junction and Storage Temperature		T <sub>J</sub> , T <sub>stg</sub>	-55 to 150	°C	
Continuous Source Current (Body Diode)		I <sub>S</sub>	6.0	A	
Single Pulse Drain-to-Source Avalanche Energy (V <sub>DD</sub> = 25 V, V <sub>GS</sub> = 10 V, I <sub>PK</sub> = 30 A, L = 1 mH, R <sub>G</sub> = 25 Ω)		E <sub>AS</sub>	450	mJ	
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)		T <sub>L</sub>	260	°C	

Maximum ratings are those values beyond which device damage can occur. Maximum ratings applied to the device are individual stress limit values (not normal operating conditions) and are not valid simultaneously. If these limits are exceeded, device functional operation is not implied, damage may occur and reliability may be affected.

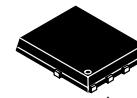
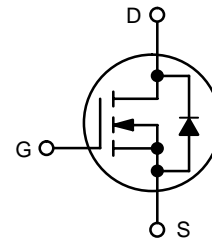
1. Surface-mounted on FR4 board using 1" sq. pad size (Cu area = 1.127" sq. [1 oz] including traces).
2. Surface-mounted on FR4 board using the minimum recommended pad size (Cu area = 0.412" sq.).



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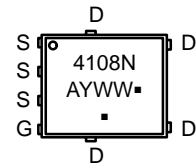
<http://onsemi.com>

V <sub>(BR)DSS</sub>	R <sub>DS(on)</sub> TYP	I <sub>D</sub> MAX
30 V	1.8 mΩ @ 10 V	35 A
	2.7 mΩ @ 4.5 V	



SO-8 FLAT LEAD  
CASE 488AA  
STYLE 1

#### MARKING DIAGRAM



4108N = Specific Device Code  
 A = Assembly Location  
 Y = Year  
 WW = Work Week  
 ■ = Pb-Free Package  
 (Note: Microdot may be in either location)

#### ORDERING INFORMATION

Device	Package	Shipping†
NTMFS4108NT1G	SO-8 FL (Pb-Free)	1500 Tape / Reel
NTMFS4108NT3G	SO-8 FL (Pb-Free)	5000 Tape / Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

# NTMFS4108N

## THERMAL RESISTANCE RATINGS

Rating	Symbol	Max	Unit
Junction-to-Ambient – Steady State (Note 3)	$R_{\theta JA}$	53	°C/W
Junction-to-Ambient – $t \leq 10$ s (Note 3)	$R_{\theta JA}$	20	
Junction-to-Ambient – Steady State (Note 4)	$R_{\theta JA}$	138	

## ELECTRICAL CHARACTERISTICS ( $T_J = 25^\circ\text{C}$ unless otherwise noted)

Characteristic	Symbol	Test Condition	Min	Typ	Max	Unit
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### OFF CHARACTERISTICS

Drain-to-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0$ V, $I_D = 250$ $\mu$ A	30			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	$V_{(BR)DSS}/T_J$			21		mV/°C
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{GS} = 0$ V, $V_{DS} = 24$ V			1.0	$\mu$ A
		$T_J = 25^\circ\text{C}$			25	
Gate-to-Source Leakage Current	$I_{GSS}$	$V_{DS} = 0$ V, $V_{GS} = 20$ V			100	nA

### ON CHARACTERISTICS (Note 5)

Gate Threshold Voltage	$V_{GS(TH)}$	$V_{GS} = V_{DS}$ , $I_D = 250$ $\mu$ A	1.0		2.5	V
Negative Threshold Temperature Coefficient	$V_{GS(TH)}/T_J$			7.5		mV/°C
Drain-to-Source On Resistance	$R_{DS(on)}$	$V_{GS} = 4.5$ V, $I_D = 19$ A		2.7	3.4	m $\Omega$
		$V_{GS} = 10$ V, $I_D = 21$ A		1.8	2.2	
Forward Transconductance	$g_{FS}$	$V_{DS} = 15$ V, $I_D = 10$ A		25		S

### CHARGES, CAPACITANCES AND GATE RESISTANCE

Input Capacitance	$C_{ISS}$	$V_{GS} = 0$ V, $f = 1.0$ MHz, $V_{DS} = 15$ V		6000		pF
Output Capacitance	$C_{OSS}$			1200		
Reverse Transfer Capacitance	$C_{RSS}$			700		
Total Gate Charge	$Q_{G(TOT)}$	$V_{GS} = 4.5$ V, $V_{DS} = 24$ V, $I_D = 21$ A		54		nC
Threshold Gate Charge	$Q_{G(TH)}$			11		
Gate-to-Source Charge	$Q_{GS}$			16		
Gate-to-Drain Charge	$Q_{GD}$			23		
Gate Resistance	$R_G$			0.7		

### SWITCHING CHARACTERISTICS, $V_{GS} = 10$ V (Note 6)

Turn-On Delay Time	$t_{d(ON)}$	$V_{GS} = 4.5$ V, $V_{DS} = 15$ V, $I_D = 1.0$ A, $R_G = 6.0$ $\Omega$		45		ns
Rise Time	$t_r$			60		
Turn-Off Delay Time	$t_{d(OFF)}$			70		
Fall Time	$t_f$			140		

### DRAIN-SOURCE DIODE CHARACTERISTICS

Forward Diode Voltage	$V_{SD}$	$V_{GS} = 0$ V, $I_S = 6.0$ A	$T_J = 25^\circ\text{C}$		0.72	1.1	V
			$T_J = 125^\circ\text{C}$		0.65		
Reverse Recovery Time	$t_{RR}$	$V_{GS} = 0$ V, $dI_S/dt = 100$ A/ $\mu$ s, $I_S = 6.0$ A			41		ns
Charge Time	$t_a$				20		
Discharge Time	$t_b$				21		
Reverse Recovery Charge	$Q_{RR}$				45		

- Surface-mounted on FR4 board using 1" sq. pad size (Cu area = 1.127" sq. [1 oz] including traces).
- Surface-mounted on FR4 board using the minimum recommended pad size (Cu area = 0.412" sq.).
- Pulse Test: Pulse Width  $\leq 300$   $\mu$ s, Duty Cycle  $\leq 2\%$ .
- Switching characteristics are independent of operating junction temperatures.

TYPICAL PERFORMANCE CURVES

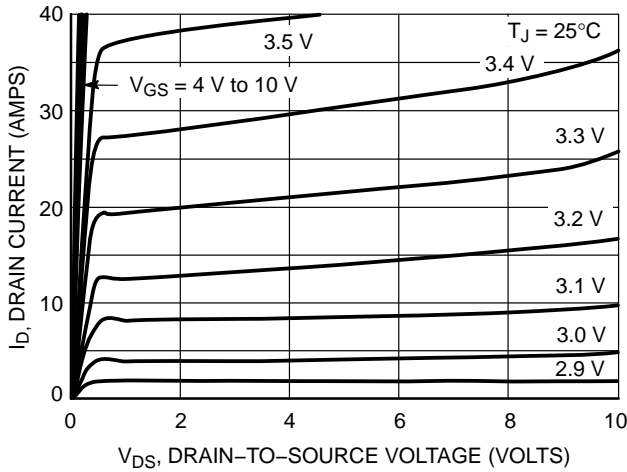


Figure 1. On-Region Characteristics

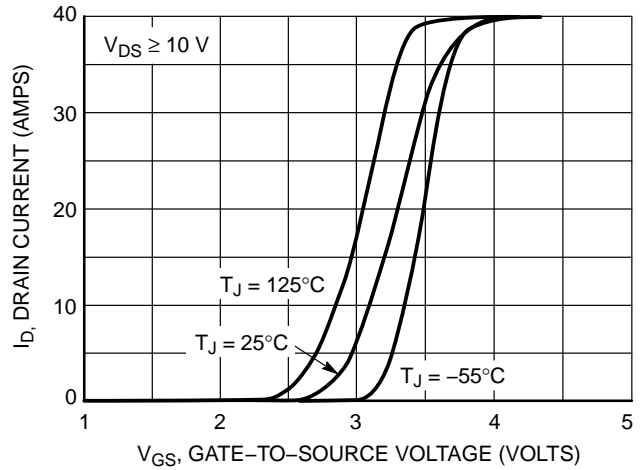


Figure 2. Transfer Characteristics

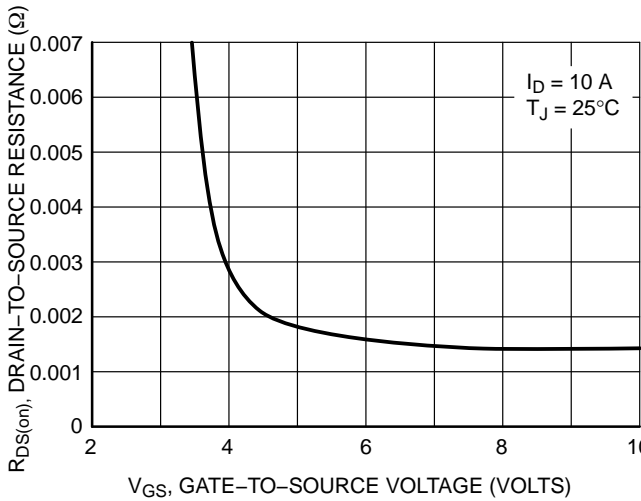


Figure 3. On-Resistance vs. Gate-to-Source Voltage

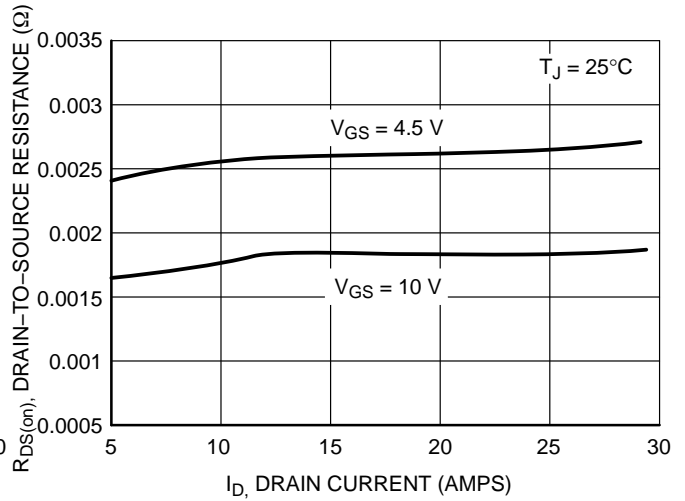


Figure 4. On-Resistance vs. Drain Current and Gate Voltage

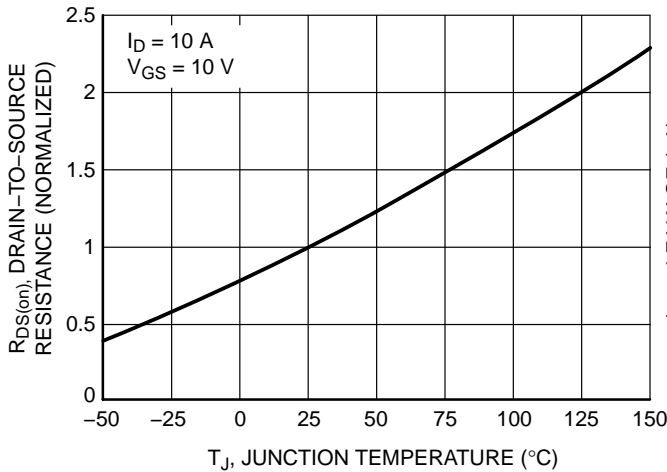


Figure 5. On-Resistance Variation with Temperature

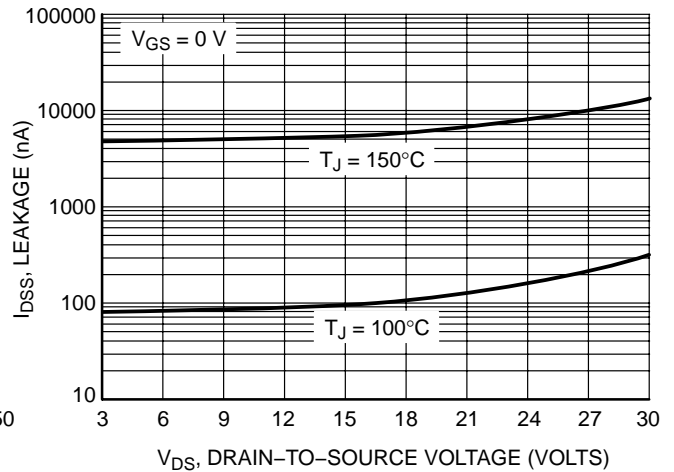


Figure 6. Drain-to-Source Leakage Current vs. Voltage

TYPICAL PERFORMANCE CURVES

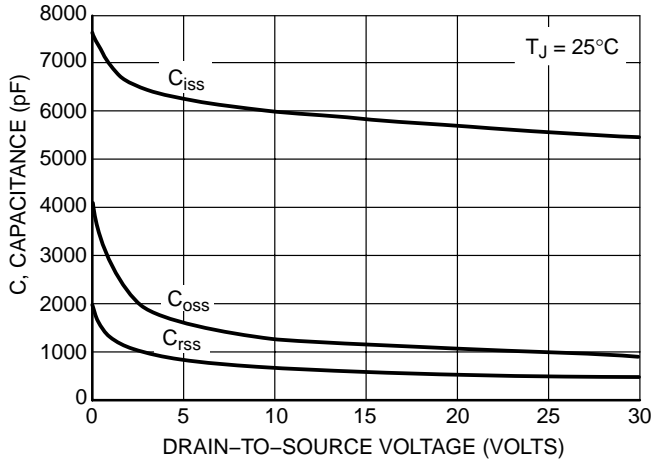


Figure 7. Capacitance Variation

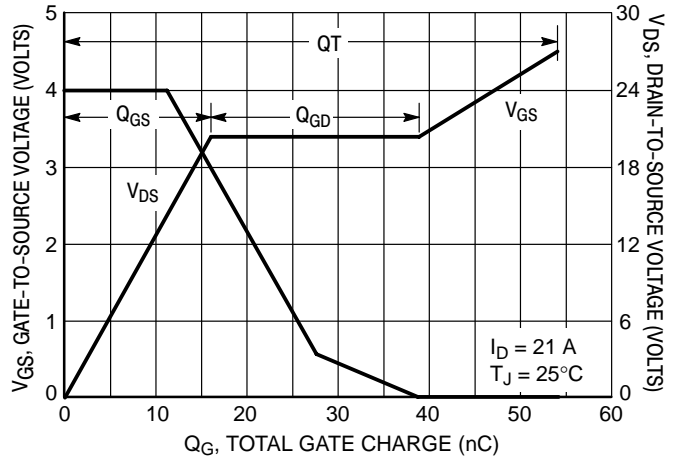


Figure 8. Gate-To-Source and Drain-To-Source Voltage vs. Total Charge

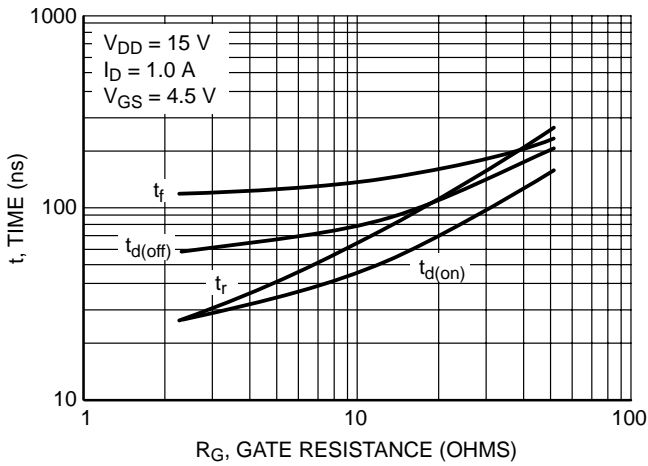


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

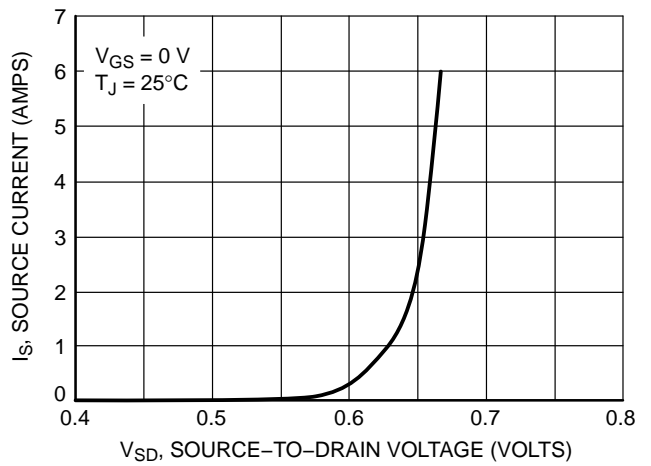
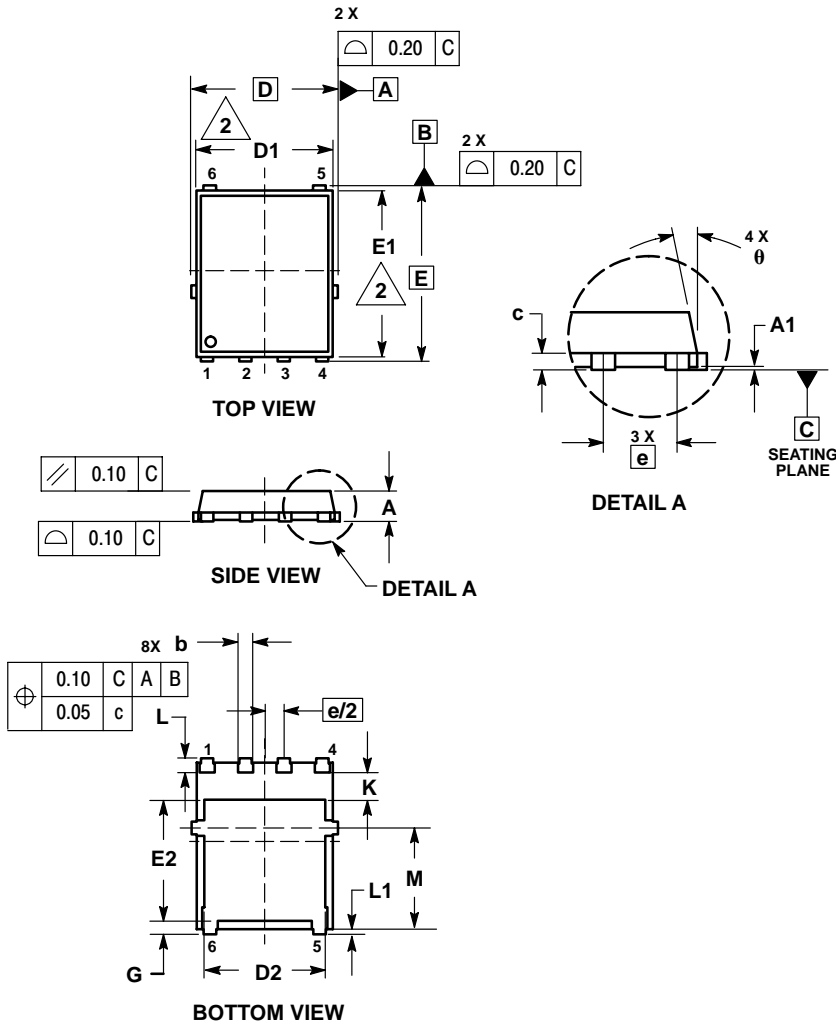


Figure 10. Diode Forward Voltage vs. Current

# NTMFS4108N

## PACKAGE DIMENSIONS

SO-8 FLAT LEAD (DFN6)  
CASE 488AA-01  
ISSUE B




- NOTES:
1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
  2. CONTROLLING DIMENSION: MILLIMETER.
  3. DIMENSION D1 AND E1 DO NOT INCLUDE MOLD FLASH PROTRUSIONS OR GATE BURRS.

DIM	MILLIMETERS		
	MIN	NOM	MAX
A	0.90	0.99	1.20
A1	0.00	---	0.05
b	0.33	0.41	0.51
c	0.23	0.28	0.33
D	5.15 BSC		
D1	4.50	4.90	5.10
D2	3.50	---	4.22
E	6.15 BSC		
E1	5.50	5.80	6.10
E2	3.45	---	4.30
e	1.27 BSC		
G	0.51	0.61	0.71
K	0.51	---	---
L	0.51	0.61	0.71
L1	0.05	0.17	0.20
M	3.00	3.40	3.80
θ	0 °	---	12 °

- STYLE 1:
1. SOURCE
  2. SOURCE
  3. SOURCE
  4. GATE
  5. DRAIN
  6. DRAIN

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